

Notice of References Cited	Application/Control No. 10/624,327	Applicant(s)/Patent Under Reexamination LEE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0105017	08-2002	Kim et al.	257/295
	B	US-2002/0196653	12-2002	Kim et al.	365/100
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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